# **Near Infrared Spectrometer**





# SM304

#### Near-Infrared (NIR) Spectrometer

User Selectable various NIR Range from 0.9 - 2.5  $\mu m$ 

Low Dark Noise and High Stability

Best Performance for NIR Spectroscopy

Wide dynamic range and high signal to noise ratio

**Optical Dark Option (Auto Shutter)** 

#### The Choice for Low Signal Level NIR Applications

Spectral Products is offering the new SM304 TE cooled InGaAs / Extended-InGaAs array spectrometers. The SM304 series are ideal for NIR spectroscopic measurement that requires very high signal to noise ratio and/or high dynamic rang through 0.9 - 2.5  $\mu$ m spectral range.

SPECTRAL PRODUCTS

The high performance with low-noise level of the SM304 series makes it possible to apply in very demanding applications. The good sensitivity of the detectors used in the SM304 series allows various broad-band applications like, measuring optical properties of solid/liquid/gas samples in NIR range, analyzing chemical components and detection of moisture, as well as a narrow band applications like NIR laser characterization.

Standard interface of the SM304 series is a USB 1.1/2.0 compatible interface with 16-bit AD conversion. Software support includes an SDK and DLLs for dedicated applications development and Windows OS-based spectral acquisition and analysis software(SM32ProMX).

Spectral Products
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# **Specifications:**

Feature	Value							
Models	SM304-512	SM304-512-2.2	SM304-512-2.5	SM304-256-2.1	SM304-256-2.5			
Detectors	G9204-512	G9206-512	G9208-512	G9206-256	G9208-256			
Pixel Size	25 X 500 μm	25 X 250 μm		50 X 500 μm				
Spectrograph f-number	3.3							
Dark	Auto Shutter							
Dark Noise RMS	6 @100ms		16 @10ms	6 @100ms	8 @10ms			
Signal to Noise Ratio (SNR)	>15,000 : 1 @100 ms		>10,000 : 1 @ 100 ms		>7,500 : 1 @ 10 ms			
Spectral Response Range	0.9-1.7 μm	0.9-2.2 μm	0.9-2.5 μm	0.9-2.0 5µm	0.9-2.5 μm			
Order Sorting Filter	Longpass filter or linear variable filter installed according to wavelength coverage							
Optical Resolution (Max. with 25 um or 50 um slit)	>3 nm overall	>4.5 nm overall	>5.5 nm overall	>7.0 nm overall	>9.0 nm overall			
Stray Light	<0.01 % at 632 nm (<0.05 % Ave)							
Fiber Coupling	SMA905 or FC/PC standard							
Computer interface	USB 1.1/2.0 compatible							
Minimum integration time	1 msec							
Trigger Mode	Free Run Mode							
	Software Trigger Mode							
	External trigger mode (9-pin connector) : TTL Edge trigger input/digital output for monitoring							
Dimensions	6.81 X 4.72 X 2.95 inches (173 X 120 X 75 mm)							
Weight	4.4lbs (2.0 kg)							
Software	SM32ProMX							
	Includes DLL libraries and SDKs for user customized application development							

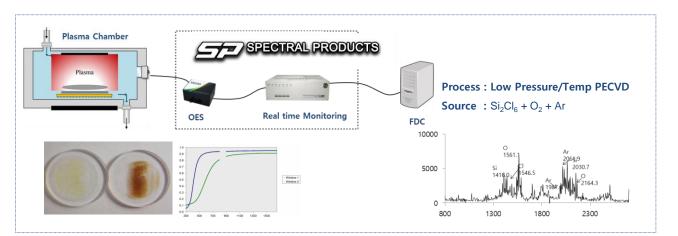
#### **Resolution Chart:**

Feature	Value						
Models	SM304-512	SM304-512-2.2	SM304-512-2.5	SM304-256-2.1	SM304-256-2.5		
Spectral Response Range	0.9-1.7 μm	0.9-2.2 μm	0.9-2.5 μm	0.9-2.05 μm	0.9-2. 5µm		
Slit Width (µm)	Max. Optical Resolution (FWHM, nm)						
25	3	4.5	5.5	-	-		
50	-	-	-	7.0	9.0		

Note) Optical Resolution Value : Average

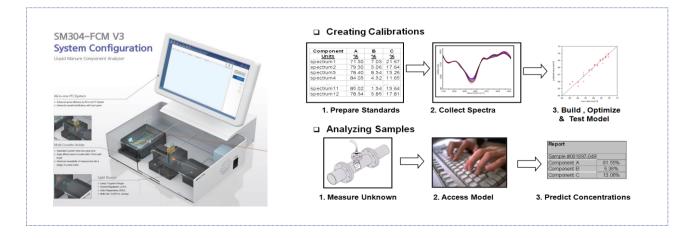
# NIR OES Sensor for Plasma Diagnostics

- Long term usage resistant to view port pollution for plasma diagnostics in semiconductor fabrications
- Extended spectral range of OES(optical emission spectroscopy) sensor up to 2.5 μm



# Real time NIR Spectrophotometer

- Real time measurement of transmission and absorption without mechanical grating rotation / scanning
- Analysis and optical monitoring of various solid / liquid / gas samples (Chemicals, Liquid Fertilizer, etc.)
- Customized calibration formula by use of signal processing, chemo-metrics and statistical algorithms

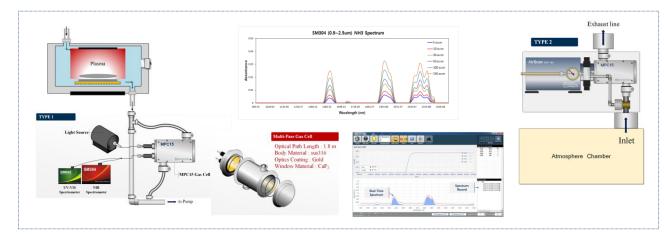






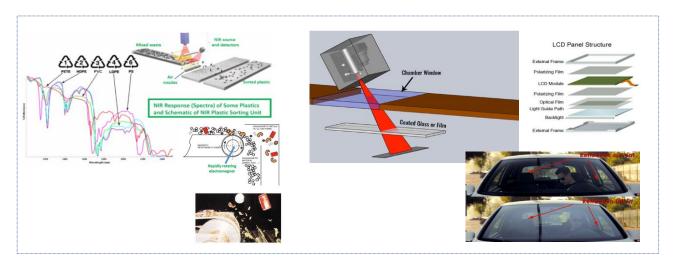
#### Optical Monitoring of Gas and Water Vapor

- In-Situ quantitative optical monitoring of vacuum / atmospheric gases and water vapor
- Customized configuration for various applications in laboratories and industrial factories

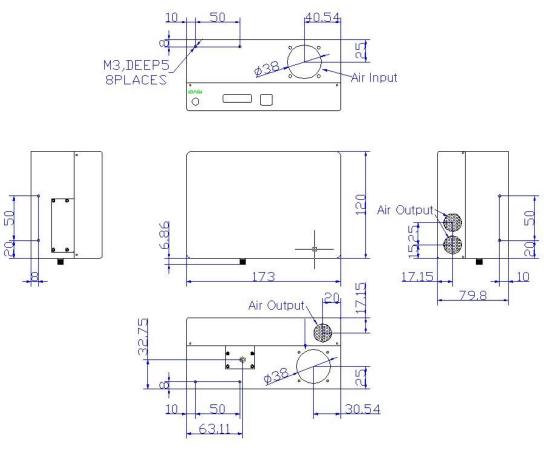


#### Analysis of optical & chemical properties of films and materials

- Measurement of thickness and optical properties of high thickness films
- Measurement of reflectance and transmittance (absorbance) of various materials (plastic, film, etc.)



### **Case Dimension:**



Units in mm

**Ordering Information :** Please indicate product number and description when ordering

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